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Substitute for form 1448A/PTO		<b>Complete If Known</b>			
<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (use as many sheets as necessary)		Application Number	10/077,784		
		Filing Date	February 20, 2002		
		First Named Inventor	Terry L. Gilton		
		Art Unit	2818		
		Examiner Name	Not Yet Assigned		
Sheet	1	of	8	Attorney Docket Number	M4065.0482/P482

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code* (if known)			
	AA	5,761,115	06/02/1998	Kozicki et al.	
	AB	6,084,796	07/04/2000	Kozicki et al.	
	AC	5,914,893	06/22/1999	Kozicki et al.	
	AD	5,896,312	04/20/1999	Kozicki et al.	
	AE	6,388,324	05/14/2002	Kozicki et al.	
	AF	US 2002/0000666	01/03/2002	Kozicki et al.	
	AG	5,500,532	03/19/1996	Kozicki et al.	
	AH	6,418,049	07/09/2002	Kozicki et al.	
	AI	5,751,012	05/12/1998	Wolstenholme et al.	
	AJ	5,789,277	08/04/1998	Zahorik et al.	
	AK	6,348,365	02/19/2002	Moore et al.	
	AL				
	AM				
	AN				
	AO				

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T <sup>2</sup>
		Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)					
	BA	WO 02/21542		03/14/2002	Kozicki et al.		
	BB	WO 00/48196		08/17/2000	Kozicki et al.		
	BC	WO 97/48032		12/18/1997	Kozicki et al.		
	BD	WO 99/28914		06/10/1999	Kozicki et al.		

Examiner Signature		Date Considered	
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\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet	2	of	8	Attorney Docket Number	M4065.0482/P482
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**OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS**

Examiner Initials	Cite No.	Include name of the author (in CAPITAL LETTERS); title of the article (when appropriate); title of the item (book, magazine, journal, serial, symposium, catalog, etc.); date; page(s); volume-issue number(s); publisher; city and/or country where published.	T <sup>2</sup>
	CA	Abdel-Ali, A.; Elshafie, A.; Elhawary, M.M.; DC electric-field effect in bulk and thin-film Ge <sub>5</sub> As <sub>38</sub> Te <sub>57</sub> chalcogenide glass, Vacuum 59 (2000) 845-853.	
	CB	Adler, D.; Moss, S.C.; Amorphous memories and bistable switches, J. Vac. Sci. Technol. 9 (1972) 1182-1189.	
	CC	Adler, D.; Henisch, H.K.; Mott, S.N.; The mechanism of threshold switching in amorphous alloys, Rev. Mod. Phys. 50 (1978) 209-220.	
	CD	Affif, M.A.; Labib, H.H.; El-Fazary, M.H.; Fadel, M.; Electrical and thermal properties of chalcogenide glass system Se <sub>75</sub> Ge <sub>25-x</sub> Sb <sub>x</sub> , Appl. Phys. A 55 (1992) 167-169.	
	CE	Affif, M.A.; Labib, H.H.; Fouad, S.S.; El-Shazly, A.A.; Electrical & thermal conductivity of the amorphous semiconductor GexSe <sub>1-x</sub> , Egypt. J. Phys. 17 (1988) 335-342.	
	CF	Alekperova, Sh.M.; Gadzhieva, G.S.; Current-Voltage characteristics of Ag <sub>2</sub> Se single crystal near the phase transition, Inorganic Materials 23 (1987) 137-139.	
	CG	Aleksiejunas, A.; Cesnys, A.; Switching phenomenon and memory effect in thin-film heterojunction of polycrystalline selenium-silver selenide, Phys. Stat. Sol. (a) 19 (1973) K169-K171.	
	CH	Angell, C.A.; Mobile ions in amorphous solids, Annu. Rev. Phys. Chem. 43 (1992) 693-717.	
	CI	Aniya, M.; Average electronegativity, medium-range-order, and ionic conductivity in superionic glasses, Solid State Ionics 136-137 (2000) 1085-1089.	
	CJ	Asahara, Y.; Izumitani, T.; Voltage controlled switching in Cu-As-Se compositions, J. Non-Cryst. Solids 11 (1972) 97-104.	
	CK	Asokan, S.; Prasad, M.V.N.; Parthasarathy, G.; Gopal, E.S.R.; Mechanical and chemical thresholds in IV-VI chalcogenide glasses, Phys. Rev. Lett. 62 (1989) 808-810.	
	CL	Baranovskii, S.D.; Cordes, H.; On the conduction mechanism in ionic glasses, J. Chem. Phys. 111 (1999) 7546-7557.	
	CM	Belin, R.; Tallades, G.; Pradel, A.; Ribes, M.; Ion dynamics in superionic chalcogenide glasses: complete conductivity spectra, Solid state Ionics 136-137 (2000) 1025-1029.	
	CN	Belin, R.; Zerouale, A.; Pradel, A.; Ribes, M.; Ion dynamics in the argyrodite compound Ag <sub>7</sub> GeSe <sub>51</sub> : non-Arrhenius behavior and complete conductivity spectra, Solid State Ionics 143 (2001) 445-455.	
	CO	Benmore, C.J.; Salmon, P.S.; Structure of fast ion conducting and semiconducting glassy chalcogenide alloys, Phys. Rev. Lett. 73 (1994) 264-267.	
	CP	Bernede, J.C.; Influence du metal des electrodes sur les caracteristiques courant-tension des structures M-Ag <sub>2</sub> Se-M, Thin solid films 70 (1980) L1-L4.	
	CQ	Bernede, J.C.; Polarized memory switching in MIS thin films, Thin Solid Films 81 (1981) 155-160.	
	CR	Bernede, J.C.; Switching and silver movements in Ag <sub>2</sub> Se thin films, Phys. Stat. Sol. (a) 57 (1980) K101-K104.	
	CS	Bernede, J.C.; Abachi, T.; Differential negative resistance in metal/insulator/metal structures with an upper bilayer electrode, Thin solid films 131 (1985) L61-L64.	
	CT	Bernede, J.C.; Conan, A.; Fousenan't, E.; El Bouchairi, B.; Goureaux, G.; Polarized memory switching effects in Ag <sub>2</sub> Se/Sa/M thin film sandwiches, Thin solid films 97 (1982) 165-171.	
	CU	Bernede, J.C.; Khelil, A.; Kettaf, M.; Conan, A.; Transition from S- to N-type differential negative resistance in Al-AI <sub>2</sub> O <sub>3</sub> -Ag <sub>2</sub> -xSe <sub>1-x</sub> thin film structures, Phys. Stat. Sol. (a) 74 (1982) 217-224.	
	CV	Bondarev, V.N.; Pikhitsa, P.V.; A dendrite model of current instability in RbAg <sub>4</sub> I <sub>5</sub> , Solid State Ionics 70/71 (1994) 72-76.	
	CW	Boolchand, P.; The maximum in glass transition temperature (T <sub>g</sub> ) near x=1/3 in GexSe <sub>1-x</sub>	



Substitute for form 1449B/PTO		Complete If Known	
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	Glasses, Asian Journal of Physics, (2000) 9, 709-72.	
CX	Boalchand, P.; Bresser, W.J.; Mobile silver ions and glass formation in solid electrolytes, Nature 410 (2001) 1070-1073.	
CY	Boalchand, P.; Georgiev, D.G.; Goodman, B.; Discovery of the Intermediate Phase in Chalcogenide Glasses, J. Optoelectronics and Advanced Materials, 3 (2001), 703	
CZ	Boalchand, P.; Selvanathan, D.; Wang, Y.; Georgiev, D.G.; Bresser, W.J., Onset of rigidity in steps in chalcogenide glasses, Properties and Applications of Amorphous Materials, M.F. Thorpe and Tichy, L. (eds.) Kluwer Academic Publishers, the Netherlands, 2001, pp. 97-132.	
CA1	Boalchand, P.; Enzweiler, R.N.; Tenhover, M.; Structural ordering of evaporated amorphous chalcogenide alloy films: role of thermal annealing, Diffusion and Defect Data Vol. 53-54 (1987) 415-420.	
CB1	Boalchand, P.; Grothaus, J.; Bresser, W.J.; Suranyi, P.; Structural origin of broken chemical order in a GeSe2 glass, Phys. Rev. B, 25 (1982) 2975-2978.	
CC1	Boalchand, P.; Grothaus, J.; Phillips, J.C.; Broken chemical order and phase separation in GexSe1-x glasses, Solid state comm. 45 (1983) 183-185.	
CD1	Boalchand, P.; Bresser, W.J.; Compositional trends in glass transition temperature (Tg), network connectivity and nanoscale chemical phase separation in chalcogenides, Dept. of ECECS, Univ. Cincinnati (October 28, 1999) 45221-0030.	
CE1	Boalchand, P.; Grothaus, J.; Molecular Structure of Melt-Quenched GeSe2 and GeS2 glasses compared, Proc. Int. Conf. Phys. Semicond. (Eds. Chadi and Harrison), 17 <sup>th</sup> (1985) 833-36.	
CF1	Bresser, W.; Boalchand, P.; Suranyi, P.; Rigidity percolation and molecular clustering in network glasses, Phys. Rev. Lett. 56 (1986) 2493-2496.	
CG1	Bresser, W.; Boalchand, P.; Suranyi, P.; de Neufville, J.P.; Intrinsically broken chalcogen chemical order in stoichiometric glasses, Journal de Physique 42 (1981) C4-193-C4-196.	
CH1	Bresser, W.; Boalchand, P.; Suranyi, P.; Hernandez, J.G.; Molecular phase separation and cluster size in GeSe2 glass, Hyperfine Interactions 27 (1986) 389-392.	
CI1	Cahen, D.; Gilet, J.-M.; Schmitz, C.; Chemyak, L.; Gartsman, K.; Jakubowicz, A.; Room-Temperature, electric field induced creation of stable devices in CulnSe2 Crystals, Science 258 (1992) 271-274.	
CJ1	Chatterjee, R.; Asokan, S.; Titus, S.S.K.; Current-controlled negative-resistance behavior and memory switching in bulk As-Te-Se glasses, J. Phys. D: Appl. Phys. 27 (1994) 2624-2627.	
CK1	Chen, C.H.; Tai, K.L.; Whisker growth induced by Ag photodoping in glassy GexSe1-x films, Appl. Phys. Lett. 37 (1980) 1075-1077.	
CL1	Chen, G.; Cheng, J.; Role of nitrogen in the crystallization of silicon nitride-doped chalcogenide glasses, J. Am. Ceram. Soc. 82 (1999) 2934-2936.	
CM1	Chen, G.; Cheng, J.; Chen, W.; Effect of Si3N4 on chemical durability of chalcogenide glass, J. Non-Cryst. Solids 220 (1997) 249-253.	
CN1	Cohen, M.H.; Neale, R.G.; Paskin, A.; A model for an amorphous semiconductor memory device, J. Non-Cryst. Solids 8-10 (1972) 885-891.	
CO1	Croitoru, N.; Lazarescu, M.; Popescu, C.; Teinic, M.; and Vescan, L.; Ohmic and non-ohmic conduction in some amorphous semiconductors, J. Non-Cryst. Solids 8-10 (1972) 781-786.	
CP1	Dalven, R.; Gill, R.; Electrical properties of beta-Ag2Te and beta-Ag2Se from 4.2 to 300K, J. Appl. Phys. 38 (1967) 753-756.	
CQ1	Davis, E.A.; Semiconductors without form, Search 1 (1970) 152-155.	
CR1	Deamaley, G.; Stoneham, A.M.; Morgan, D.V.; Electrical phenomena in amorphous oxide films, Rep. Prog. Phys. 33 (1970) 1129-1191.	
CS1	Dejus, R.J.; Susman, S.; Volin, K.J.; Montague, D.G.; Price, D.L.; Structure of Vitreous Ag-Ge-Se, J. Non-Cryst. Solids 143 (1992) 162-180.	
CT1	den Boer, W.; Threshold switching in hydrogenated amorphous silicon, Appl. Phys. Lett. 40 (1982) 812-813.	
CU1	Drusedau, T.P.; Panckow, A.N.; Klabunde, F.; The hydrogenated amorphous	



Substitute for form 1449B/PTO

# INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(use as many sheets as necessary)

Sheet	4	of	8	Application Number	10/077,784
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## Complete If Known

Filing Date	February 20, 2002
First Named Inventor	T rry L. Gilton
Group Art Unit	2818
Examiner Name	Not Yet Assigned
Attorney Docket Number	M4065.0482/P482

		silicon/nanodisperse metal (SIMAL) system-Films of unique electronic properties, J. Non-Cryst. Solids 198-200 (1996) 829-832.	
CV1		El Bouchalr, B.; Bernede, J.C.; Burgaud, P., Properties of Ag <sub>2</sub> -xSe <sub>1+x/n</sub> -Si diodes, Thin Solid Films 110 (1983) 107-113.	
CW1		El Gharnas, Z.; Bourahla, A.; Vautier, C., Role of photoinduced defects in amorphous Ge <sub>x</sub> Se <sub>1-x</sub> photoconductivity, J. Non-Cryst. Solids 155 (1993) 171-179.	
CX1		El Ghrandi, R.; Calas, J.; Galibert, G.; Averous, M., Silver photodissolution in amorphous chalcogenide thin films, Thin Solid Films 218 (1992) 259-273.	
CY1		El Ghrandi, R.; Calas, J.; Galibert, G., Ag dissolution kinetics in amorphous GeSe <sub>5.5</sub> thin films from "in-situ" resistance measurements vs time, Phys. Stat. Sol. (a) 123 (1991) 451-460.	
CZ1		El-kady, Y.L., The threshold switching in semiconducting glass Ge <sub>21</sub> Se <sub>17</sub> Te <sub>62</sub> , Indian J. Phys. 70A (1996) 507-516.	
CA2		Elliott, S.R., A unified mechanism for metal photodissolution in amorphous chalcogenide materials, J. Non-Cryst. Solids 130 (1991) 85-97.	
CB2		Elliott, S.R., Photodissolution of metals in chalcogenide glasses: A unified mechanism, J. Non-Cryst. Solids 137-138 (1991) 1031-1034.	
CC2		Elsamanoudy, M.M.; Hegab, N.A.; Fadel, M., Conduction mechanism in the pre-switching state of thin films containing Te-As-Ge-Si, Vacuum 46 (1995) 701-707.	
CD2		El-Zahed, H.; El-Korashy, A., Influence of composition on the electrical and optical properties of Ge <sub>20</sub> Bi <sub>10</sub> Se <sub>80-x</sub> films, Thin Solid Films 376 (2000) 236-240.	
CE2		Fadel, M., Switching phenomenon in evaporated Se-Ge-As thin films of amorphous chalcogenide glass, Vacuum 44 (1993) 851-855.	
CF2		Fadel, M.; El-Shahr, H.T., Electrical, thermal and optical properties of Se <sub>75</sub> Ge <sub>7</sub> Sb <sub>18</sub> , Vacuum 43 (1992) 253-257.	
CG2		Feng, X.; Bresser, W.J.; Boolchand, P., Direct evidence for stiffness threshold in Chalcogenide glasses, Phys. Rev. Lett. 78 (1997) 4422-4425.	
CH2		Feng, X.; Bresser, W.J.; Zhang, M.; Goodman, B.; Boolchand, P., Role of network connectivity on the elastic, plastic and thermal behavior of covalent glasses, J. Non-Cryst. Solids 222 (1997) 137-143.	
CI2		Fischer-Colbric, A.; Blenenstock, A.; Fuoss, P.H.; Marcus, M.A., Structure and bonding in photodiffused amorphous Ag-GeSe <sub>2</sub> thin films, Phys. Rev. B 38 (1988) 12388-12403.	
CJ2		Fleury, G.; Hamou, A.; Viger, C.; Vautier, C., Conductivity and crystallization of amorphous selenium, Phys. Stat. Sol. (a) 64 (1981) 311-316.	
CK2		Fritzsche, H., Optical and electrical energy gaps in amorphous semiconductors, J. Non-Cryst. Solids 6 (1971) 49-71.	
CL2		Fritzsche, H., Electronic phenomena in amorphous semiconductors, Annual Review of Materials Science 2 (1972) 697-744.	
CM2		Gates, B.; Wu, Y.; Yin, Y.; Yang, P.; Xia, Y., Single-crystalline nanowires of Ag <sub>2</sub> Se can be synthesized by templating against nanowires of trigonal Se, J. Am. Chem. Soc. (2001) currently ASAP.	
CN2		Gosain, D.P.; Nakamura, M.; Shimizu, T.; Suzuki, M.; Okano, S., Nonvolatile memory based on reversible phase transition phenomena in telluride glasses, Jap. J. Appl. Phys. 28 (1989) 1013-1018.	
CO2		Guin, J.-P.; Rouxel, T.; Keryvin, V.; Sangleboeuf, J.-C.; Serre, I.; Lucas, J., Indentation creep of Ge-Se chalcogenide glasses below T <sub>g</sub> : elastic recovery and non-Newtonian flow, J. Non-Cryst. Solids 298 (2002) 260-269.	
CP2		Guin, J.-P.; Rouxel, T.; Sangleboeuf, J.-C.; Melscoet, I.; Lucas, J., Hardness, toughness, and scratchability of germanium-selenium chalcogenide glasses, J. Am. Ceram. Soc. 85 (2002) 1545-52.	
CQ2		Gupta, Y.P., On electrical switching and memory effects in amorphous chalcogenides, J. Non-Cryst. Sol. 3 (1970) 148-154.	





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Sheet	5	of	8

CR2	Haberland, D.R.; Stiegler, H.; New experiments on the charge-controlled switching effect in amorphous semiconductors, J. Non-Cryst. Solids 8-10 (1972) 408-414.
CS2	Halfz, M.M.; Ibrahim, M.M.; Dongol, M.; Hammad, F.H.; Effect of composition on the structure and electrical properties of As-Se-Cu glasses, J. Appl. Phys. 54 (1983) 1950-1954.
CT2	Hajto, J.; Rose, M.J.; Osborne, I.S.; Snell, A.J.; Le Comber, P.G.; Owen, A.E.; Quantization effects in metal/a-Si:H/metal devices, Int. J. Electronics, 73 (1992) 911-913.
CU2	Hajto, J.; Hur, J.; Snell, A.J.; Turvey, K.; Rose, M.J.; DC and AC measurements on metal/a-Si:H/metal room temperature quantized resistance devices, J. Non-Cryst. Solids 266-269 (2000) 1058-1061.
CV2	Hajto, J.; McAuley, B.; Snell, A.J.; Owen, A.E.; Theory of room temperature quantized resistance effects in metal-a-Si:H-metal thin film structures, J. Non-Cryst. Solids 198-200 (1996) 825-828.
CW2	Hajto, J.; Owen, A.E.; Snell, A.J.; Le Comber, P.G.; Rose, M.J.; Analogue memory and ballistic electron effects in metal-amorphous silicon structures, Phil. Mag. B 63 (1991) 349-369.
CX2	Hayashi, T.; Ono, Y.; Fukaya, M.; Kan, H.; Polarized memory switching in amorphous Se film, Japan. J. Appl. Phys. 13 (1974) 1163-1164.
CY2	Hegab, N.A.; Fadel, M.; Sedeek, K.; Memory switching phenomena in thin films of chalcogenide semiconductors, Vacuum 45 (1994) 459-462.
CZ2	Hirose, Y.; Hirose, H.; Polarity-dependent memory switching and behavior of Ag dendrite in Ag-photodoped amorphous As <sub>2</sub> S <sub>3</sub> films, J. Appl. Phys. 47 (1976) 2767-2772.
CA3	Hong, K.S.; Speyer, R.E.; Switching behavior in II-IV-V <sub>2</sub> amorphous semiconductor systems, J. Non-Cryst. Solids 116 (1990) 191-200.
CB3	Hosokawa, S.; Atomic and electronic structures of glassy GexSe1-x around the stiffness threshold composition, J. Optoelectronics and Advanced Materials 3 (2001) 199-214.
CC3	Hu, J.; Snell, A.J.; Hajto, J.; Owen, A.E.; Constant current forming in Cr/p+a-Si:H/V thin film devices, J. Non-Cryst. Solids 227-230 (1998) 1187-1191.
CD3	Hu, J.; Snell, A.J.; Owen, A.E.; Rose, M.J.; Capacitance anomaly near the metal-non-metal transition in Cr-hydrogenated amorphous Si-V thin-film devices, Phil. Mag. B. 74 (1996) 37-50.
CE3	Hu, J.; Snell, A.J.; Hajto, J.; Owen, A.E.; Current-induced instability in Cr-p+a-Si:H-V thin film devices, Phil. Mag. B 80 (2000) 29-43.
CF3	Iizima, S.; Sugii, M.; Kikuchi, M.; Tanaka, K.; Electrical and thermal properties of semiconducting glasses As-Te-Ge, Solid State Comm. 8 (1970) 153-155.
CG3	Ishikawa, R.; Kikuchi, M.; Photovoltaic study on the photo-enhanced diffusion of Ag in amorphous films of Ge <sub>2</sub> S <sub>3</sub> , J. Non-Cryst. Solids 35 & 36 (1980) 1061-1066.
CH3	Iyatomi, H.; Vashishta, P.; Kalla, R.K.; Incipient phase separation in Ag/Ge/Se glasses: clustering of Ag atoms, J. Non-Cryst. Solids 262 (2000) 135-142.
CI3	Jones, G.; Collins, R.A.; Switching properties of thin selenium films under pulsed bias, Thin Solid Films 40 (1977) L15-L18.
CJ3	Joullie, A.M.; Marucchi, J.; On the DC electrical conduction of amorphous As <sub>2</sub> Se <sub>7</sub> before switching, Phys. Stat. Sol. (a) 13 (1972) K105-K109.
CK3	Joullie, A.M.; Marucchi, J.; Electrical properties of the amorphous alloy As <sub>2</sub> Se <sub>5</sub> , Mat. Res. Bull. 8 (1973) 433-442.
CL3	Kaplan, T.; Adler, D.; Electrothermal switching in amorphous semiconductors, J. Non-Cryst. Solids 8-10 (1972) 538-543.
CM3	Kawaguchi, T.; Maruno, S.; Elliott, S.R.; Optical, electrical, and structural properties of amorphous Ag-Ge-S and Ag-Ge-Se films and comparison of photoinduced and thermally induced phenomena of both systems, J. Appl. Phys. 79 (1996) 9096-9104.
CN3	Kawaguchi, T.; Masui, K.; Analysis of change in optical transmission spectra resulting from Ag photodoping in chalcogenide film, Jpn. J. Appl. Phys. 26 (1987) 15-21.

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CO3	Kawakami M., Kawamura Y., Nakamura Y., Aniya M., Ionic conductivity of $\text{Ag}_x(\text{GeSe}_3)_{1-x}$ ( $0 < x < 0.57$ ), glasses, Solid State Ionics 123 (1999) 259-269.
CP3	Kuge G., Thomas A., Klabes R., Grotzschel R., Silver photodiffusion in amorphous $\text{GeSe}_{100-x}\text{Te}_x$ Non-Cryst Solids 124 (1990) 186-193.
CQ3	Kolobov A.V., On the origin of p-type conductivity in amorphous chalcogenides, J. Non-Cryst. Solids 198-200 (1996) 726-731.
CR3	Kolobov A.V., Lateral diffusion of silver in vitreous chalcogenide films, J. Non-Cryst. Solids 137-138 (1991) 1027-1030.
CS3	Korkinova T.E., Andreichin R.E., Chalcogenide glass: polarization and the type of contacts, J. Non-Cryst. Solids 194 (1996) 256-259.
CT3	Kotkata M.F., Afifi M.A., Labib H.H., Hegab, N.A., Abdel-Aziz, M.M., Memory switching in amorphous $\text{GeSeTe}$ chalcogenide semiconductor films, Thin Solid Films 240 (1994) 143-146.
CU3	Lakshminarayan K.N., Srivastava K.K., Panwar, O.S., Dumar, A., Amorphous semiconductor devices: memory and switching mechanism, J. Instr. Electronics & Telecom. Engrs 27 (1981) 16-19.
CV3	Lal M., Goyal N., Chemical bond approach to study the memory and threshold switching chalcogenide glasses, Indian Journal of pure & appl. phys. 29 (1991) 303-304.
CW3	Leimer F., Stobzel H., Kottwitz A., Isothermal electrical polarisation of amorphous $\text{GeSe}$ films with blocking Al contacts influenced by Poole-Frenkel conduction, Phys. Stat. Sol. (a) 29 (1975) K129-K132.
CX3	Leung W., Cheung N., Neureuther A.R., Photoinduced diffusion of Ag in $\text{GeSe}_{1-x}$ glass, Appl. Phys. Lett. 46 (1985) 543-545.
CY3	Matsushita T., Yamagami T., Okuda M., Polarized memory effect observed on $\text{Se-SnO}_2$ system, Jap. J. Appl. Phys. 11 (1972) 1657-1662.
CZ3	Matsushita T., Yamagami T., Okuda M., Polarized memory effect observed on amorphous selenium thin films, Jpn. J. Appl. Phys. 11 (1972) 606.
CA4	Mazurier F., Levy M., Souquet J.L., Reversible and irreversible electrical switching in $\text{TeO}_2\text{-V}_2\text{O}_5$ based glasses, Journal de Physique IV, 2 (1992) C2-185 - C2-188.
CB4	Messoussi R., Bernede J.C., Benhida S., Abachi T., Latif A., Electrical characterization of $\text{M}(\text{Se})$ structures ( $\text{M}=\text{Ni}, \text{Bi}$ ), Mat. Chem. And Phys. 28 (1991) 253-258.
CC4	Mitkova M., Boolchand P., Microscopic origin of the glass forming tendency in chalcogenides and constraint theory, J. Non-Cryst. Solids 240 (1998) 1-21.
CD4	Mitkova M., Kozicki M.N., Silver incorporation in $\text{Ge-Se}$ glasses used in programmable metallization cell devices, J. Non-Cryst. Solids 299-302 (2002) 1023-1027.
CE4	Mitkova M., Wang Y., Boolchand P., Dual chemical role of Ag as an additive in chalcogenide glasses, Phys. Rev. Lett. 83 (1999) 3848-3851.
CF4	Miyatani S.-y., Electronic and ionic conduction in $\text{AgxCu}_{1-x}\text{Se}_2$ , J. Phys. Soc. Japan 34 (1973) 423-432.
CG4	Miyatani S.-y., Electrical properties of $\text{Ag}_2\text{Se}$ , J. Phys. Soc. Japan 13 (1958) 317.
CH4	Miyatani S.-y., Ionic conduction in beta- $\text{Ag}_2\text{Te}$ and beta- $\text{Ag}_2\text{Se}$ , Journal Phys. Soc. Japan 14 (1959) 998-1002.
CI4	Mott N.F., Conduction in glasses containing transition metal ions, J. Non-Cryst. Solids 1 (1968) 1-17.
CJ4	Nakayama K., Kitagawa T., Ohmura M., Suzuki M., Nonvolatile memory based on phase transitions in chalcogenide thin films, Jpn. J. Appl. Phys. 32 (1993) 584-589.
CK4	Nakayama K., Kojima K., Hayakawa F., Imai Y., Kitagawa A., Suzuki M., Submicron nonvolatile memory cell based on reversible phase transition in chalcogenide glasses, Jpn. J. Appl. Phys. 39 (2000) 6157-6161.
CL4	Nang T.T., Okuda M., Matsushita T., Yokota S., Suzuki A., Electrical and optical parameters of $\text{GeSe}_{1-x}$ amorphous thin films, Jap. J. App. Phys. 15 (1976) 849-853.
CM4	Narayanan R.A., Asokan S., Kumar A., Evidence concerning the effect of topology on

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Sheet	7	of	8	Attorney Docket Number	M4065.0482/P482
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		electrical switching in chalcogenide network glasses, Phys. Rev. B 54 (1996) 4413-4415.	
	CN4	Neale, R.G.; Asetline, J.A. The application of amorphous materials to computer memories, IEEE transactions on electron dev. Ed-20 (1973) 195-209.	
	CO4	Ovshinsky S.R.; Fritzche, H. Reversible structural transformations in amorphous semiconductors for memory and logic, Metallurgical transactions 2 (1971) 641-645.	
	CP4	Ovshinsky S.R. Reversible electrical switching phenomena in disordered structures, Phys. Rev. Lett. 21 (1968) 1450-1453.	
	CQ4	Owen, A.E.; LeComber, P.G.; Sarraayrouse, G.; Spear, W.E., New amorphous-silicon electrically programmable nonvolatile switching device, IEE Proc. 129 (1982) 51-54	
	CR4	Owen, A.E.; Firth, A.P.; Ewen, P.J.S., Photo-induced structural and physico-chemical changes in amorphous chalcogenide semiconductors, Phil. Mag. B 52 (1985) 347-362.	
	CS4	Owen, A.E.; LeComber, P.G.; Hajto, J.; Rose, M.J.; Snell, A.J., Switching in amorphous devices, Int. J. Electronics 73 (1992) 697-806.	
	CT4	Pearson, A.D.; Miller, C.E., Filamentary conduction in semiconducting glass diodes, App. Phys. Lett. 14 (1969) 280-282.	
	CU4	Pinto, R.; Ramanathan, K.V., Electric field induced memory switching in thin films of the chalcogenide system Ge-As-Se, Appl. Phys. Lett. 19 (1971) 221-223.	
	CV4	Popescu, C., The effect of local non-uniformities on thermal switching and high field behavior of structures with chalcogenide glasses, Solid-state electronics 18 (1975) 671-681.	
	CW4	Popescu, C.; Croitoru, N., The contribution of the lateral thermal instability to the switching phenomenon, J. Non-Cryst. Solids 8-10 (1972) 531-537.	
	CX4	Popov, A.I.; Geller, I.KH.; Shemetova, V.K., Memory and threshold switching effects in amorphous selenium, Phys. Stat. Sol. (a) 44 (1977) K71-K73.	
	CY4	Prakash, S.; Asokan, S.; Ghare, D.B., Easily reversible memory switching in Ge-As-Te glasses, J. Phys. D: Appl. Phys. 29 (1996) 2004-2008.	
	CZ4	Rahman, S.; Sivarama Sastry, G., Electronic switching in Ge-Bi-Se-Te glasses, Mat. Sci. and Eng. B12 (1992) 219-222.	
	CA5	Ramesh, K.; Asokan, S.; Sangunni, K.S.; Gopal, E.S.R., Electrical Switching in germanium telluride glasses doped with Cu and Ag, Appl. Phys. A 69 (1999) 421-425.	
	CB5	Rose, M.J.; Hajto, J.; Lecomber, P.G.; Gage, S.M.; Chol, W.K.; Snell, A.J.; Owen, A.E., Amorphous silicon analogue memory devices, J. Non-Cryst. Solids 115 (1989) 168-170.	
	CC5	Rose, M.J.; Snell, A.J.; Lecomber, P.G.; Hajto, J.; Fitzgerald, A.G.; Owen, A.E., Aspects of non-volatility in a Si:H memory devices, Mat. Res. Soc. Symp. Proc. V 258, 1992, 1075-1080.	
	CD5	Schuoocker, D.; Rieder, G., On the reliability of amorphous chalcogenide switching devices, J. Non-Cryst. Solids 29 (1978) 397-407.	
	CE5	Sharma, A.K.; Singh, B., Electrical conductivity measurements of evaporated selenium films in vacuum, Proc. Indian Natn. Sci. Acad. 46, A, (1980) 362-368.	
	CF5	Sharma, P., Structural, electrical and optical properties of silver selenide films, Ind. J. Of pure and applied phys. 35 (1997) 424-427.	
	CG5	Snell, A.J.; Lecomber, P.G.; Hajto, J.; Rose, M.J.; Owen, A.E.; Osborne, I.L., Analogue memory effects in metal/a-Si:H/metal memory devices, J. Non-Cryst. Solids 137-138 (1991) 1257-1262.	
	CH5	Snell, A.J.; Hajto, J.; Rose, M.J.; Osborne, L.S.; Holmes, A.; Owen, A.E.; Gibson, R.A.G., Analogue memory effects in metal/a-Si:H/metal thin film structures, Mat. Res. Soc. Symp. Proc. V 297, 1993, 1017-1021.	
	CI5	Steventon, A.G., Microfilaments in amorphous chalcogenide memory devices, J. Phys. D: Appl. Phys. 8 (1975) L120-L122.	
	CJ5	Steventon, A.G., The switching mechanisms in amorphous chalcogenide memory devices, J. Non-Cryst. Solids 21 (1976) 319-329.	
	CK5	Stocker, H.J., Bulk and thin film switching and memory effects in semiconducting chalcogenide glasses, App. Phys. Lett. 15 (1969) 55-57.	

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Application Number	10/077,784
Filing Date	February 20, 2002
First Named Inventor	Terry L. Gilton
Group Art Unit	2818
Examiner Name	Not Yet Assigned
Attorney Docket Number	M4065.0482/P482

Sheet	8	of	8	Attorney Docket Number	M4065.0482/P482
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CL5	Tanaka, K.; Ionic and mixed conductions in Ag photodoping process, Mod. Phys. Lett B 4 (1990) 1373-1377.	
CM5	Tanaka, K.; Izima, S.; Sugl, M.; Okada, Y.; Kikuchi, M., Thermal effects on switching phenomenon in chalcogenide amorphous semiconductors, Solid State Comm. 8 (1970) 387-389.	
CN5	Thornburg, D.D., Memory switching in a Type I amorphous chalcogenide, J. Elect. Mat. 2 (1973) 3-15.	
CO5	Thornburg, D.D., Memory switching in amorphous arsenic triselenide, J. Non-Cryst. Solids 11 (1972) 113-120.	
CP5	Thornburg, D.D.; White, R.M., Electric field enhanced phase separation and memory switching in amorphous arsenic triselenide, Journal(?) (1972) 4609-4612.	
CQ5	Tichy, L.; Ticha, H.; Remark on the glass-forming ability in GexSe1-x and AsxSe1-x systems, J. Non-Cryst. Solids 261 (2000) 277-281.	
CR5	Titus, S.S.K.; Chatterjee, R.; Asokan, S., Electrical switching and short-range order in As-Te glasses, Phys. Rev. B 48 (1993) 14650-14652.	
CS5	Tranchant, S.; Peytavin, S.; Ribes, M.; Flank, A.M.; Dexpert, H.; Lagarde, J.P., Silver chalcogenide glasses Ag-Ge-Se: Ionic conduction and exafs structural investigation, Transport-structure relations in fast ion and mixed conductors Proceedings of the 6th Riso International symposium, 9-13 September 1985.	
CT5	Tregouet, Y.; Bernede, J.C., Silver movements in Ag2Te thin films: switching and memory effects, Thin Solid Films 57 (1979) 49-54.	
CU5	Uemura, O.; Kameda, Y.; Kokai, S.; Satow, T., Thermally induced crystallization of amorphous Ge0.4Se0.6, J. Non-Cryst. Solids 117-118 (1990) 219-221.	
CV5	Uttecht, R.; Stevenson, H.; Sle, C.H.; Griener, J.D.; Raghavan, K.S., Electric field induced filament formation in As-Te-Ge glass, J. Non-Cryst. Solids 2 (1970) 358-370.	
CD5	Viger, C.; Lefrancols, G.; Fleury, G., Anomalous behaviour of amorphous selenium films, J. Non-Cryst. Solids 33 (1976) 267-272.	
CX5	Vodenicharov, C.; Parvanov, S.; Petkov, P., Electrode-limited currents in the thin-film M-GeSe-M system, Mat. Chem. And Phys. 21 (1989) 447-454.	
CY5	Wang, S.-J.; Mislum, G.R.; Camp, J.C.; Chen, K.-L.; Tigelaar, H.L., High-performance Metal/silicide antifuse, IEEE electron dev. Lett. 13 (1992) 471-472.	
CZ5	Weirauch, D.F., Threshold switching and thermal filaments in amorphous semiconductors, App. Phys. Lett. 16 (1970) 72-73.	
CA6	West, W.C.; Sieradzki, K.; Kardynal, B.; Kozicki, M.N., Equivalent circuit modeling of the AgIAs0.24S0.36Ag0.40/Ag System prepared by photodissolution of Ag, J. Electrochem. Soc. 145 (1998) 2971-2974.	
CB6	West, W.C., Electrically erasable non-volatile memory via electrochemical deposition of multifractal aggregates, Ph.D. Dissertation, ASU 1998	
CC6	Zhang, M.; Mancini, S.; Bresser, W.; Boolchand, P., Variation of glass transition temperature, Tg, with average coordination number, <m>, in network glasses: evidence of a threshold behavior in the slope  dTg/d<m>  at the rigidity percolation threshold (<m>=2.4), J. Non-Cryst. Solids 151 (1992) 149-154.	

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